INTERNATIONAL SEARCH REPORT

A. CLASSIFICATION OF SUBJECT MATTER
IPC 7   G06T7/00   G06T5/00

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
IPC 7   G06T   H04N

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, INSPEC, WPI Data

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	CAVIEDES J ET AL: "No-reference sharpness metric based on local edge kurtosis" PROCEEDINGS 2002 INTERNATIONAL CONFERENCE ON IMAGE PROCESSING. ICIP 2002. ROCHESTER, NY, SEPT. 22 - 25, 2002, INTERNATIONAL CONFERENCE ON IMAGE PROCESSING, NEW YORK, NY : IEEE, US, vol. VOL. 2 OF 3, 22 September 2002 (2002-09-22), pages 53-56, XP010607508 ISBN: 0-7803-7622-6 abstract sections 2-4 _____ -/--	1,25,26

[X] Further documents are listed in the continuation of box C.   [ ] Patent family members are listed in annex.

° Special categories of cited documents :

"A" document defining the general state of the art which is not considered to be of particular relevance

"E" earlier document but published on or after the international filing date

"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)

"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.

"&" document member of the same patent family

Date of the actual completion of the international search	Date of mailing of the international search report
18 February 2005	03/03/2005

Name and mailing address of the ISA	Authorized officer
European Patent Office, P.B. 5818 Patentlaan 2 NL – 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016	Gao, M

Form PCT/ISA/210 (second sheet) (January 2004)

BEST AVAILABLE COPY

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
P,X	CAVIEDES J ET AL: "A new sharpness metric based on local kurtosis, edge and energy information" SIGNAL PROCESSING. IMAGE COMMUNICATION, ELSEVIER SCIENCE PUBLISHERS, AMSTERDAM, NL, vol. 19, no. 2, February 2004 (2004-02), pages 147-161, XP004483132 ISSN: 0923-5965 the whole document	1-32
A	NIEN FAN ZHANG ET AL: "Image sharpness measurement in the scanning electron microscope. III" SCANNING FAMS USA, vol. 21, no. 4, July 1999 (1999-07), pages 246-252, XP008043210 ISSN: 0161-0457 section "Univariate and Multivariate Kurtosis"	1-32
A	ZHANG, N.F., POSTEK, M.T., LARRABEE, R.D., AND VLADAR, A.E.: "Multivariate Kurtosis for Measuring Image Sharpness" PROCEEDINGS OF THE 15TH INTERNATIONAL WORKSHOP ON STATISTICAL MODELING, NEW TRENDS IN STATISTICAL MODELING, 'Online! 2000, pages 529-532, XP002318335 Retrieved from the Internet: URL:https://srmors.nist.gov/referencelinks /zhang.pdf> 'retrieved on 2005-02-17! abstract	1-32

BEST AVAILABLE COPY